

Attend IEEE IRPS 2018 - Register at <http://irps.org/>

For 56 years, IRPS has been the **premier conference** for engineers and scientists to present new and original work in the area of **microelectronics reliability**. Drawing participants from the United States, Europe, Asia, and all other parts of the world, **IRPS seeks to understand the reliability of semiconductor devices, integrated circuits, and microelectronic assemblies** through an improved understanding of both the physics of failure as well as the application environment. IRPS provides numerous opportunities for attendees to **increase their knowledge and understanding of all aspects of microelectronics reliability**. It is also an outstanding chance to meet and network with reliability colleagues from around the world.

The 2018 IRPS conference program includes **20 tutorials** with tracks on the reliability of silicon, circuits, systems, memory, automotive and power applications; **3 focus sessions** on GaN/SiC reliability & qualification standardization, system level reliability, and 3D/2.5D/Packaging reliability; **platform presentations, posters and workshops** that also include circuit aging, memory, soft errors, ESD, transistors, dielectrics, photovoltaics, and interconnects. Dr. Nirmal Saxena from NVIDIA will give a **keynote** titled **"The Road to Resilient Computing in Autonomous Driving is Paved with Redundancy"**

Top 3 Reasons to Attend:

1. Listen to new and original work in the many different areas of reliability of electronic devices;
2. Increase your networking with industry leaders and professionals in the only place to have this type of exposure and training;
3. The conference is suited for a broad audience, from the reliability novice to the well-practiced engineer, including circuit and systems designers and semiconductor process experts who want to learn more about reliability.

IRPS is Co-Sponsored
by IEEE EDS and
Reliability Society



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Burlingame, CA, USA

